

del Castillo, E.**Statistical process adjustment: a brief retrospective, current status, and some opportunities for further work.** (English) [Zbl 1109.62127](#)

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Summary: Industrial statisticians frequently face problems in their practice where adjustment of a manufacturing process is necessary. In this paper, a view of the origins and recent work in the area of statistical process adjustment (SPA) are provided. A discussion of some topics open for further research is also given including new problems in semiconductor manufacturing process control. The goal of the paper is to help display the SPA field as a research area with its own identity and content, and promote further interest in its development and application in the industry.

MSC:

62P30 Applications of statistics in engineering and industry; control charts

Cited in 2 Documents

Keywords:

engineering process control; time-series control; EWMA controllers; set-up adjustment; Bayesian control; deadband adjustment

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